Searcn Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/606,138	AYYAVU ET AL.	
Examiner	Art Unit	
James K. Trujillo	2116	

	SEARCHED				
Class	Subclass	Date	Examiner		
713	300,320, 322,323, 324	12/8/2004	JKT		
updated		5/9/2005	JKT		
AA 11-25-314					
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
Interference search, see search history		9/1/2005	JKT		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Databases: EAST NPL: IEEE, ACM	12/8/2004	JKT	
updated	5/9/2005	JKT	
updated .	9/1/2005	JKT	
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